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SOLAR FACILITY AT ASU



Solar Monitoring Facility at the ASU Research Park.

- PV array consists of 104 PV panels.
- Each panel has a smart monitoring device.
- SMDs sense current, and voltage. They have sensors, and actuators.

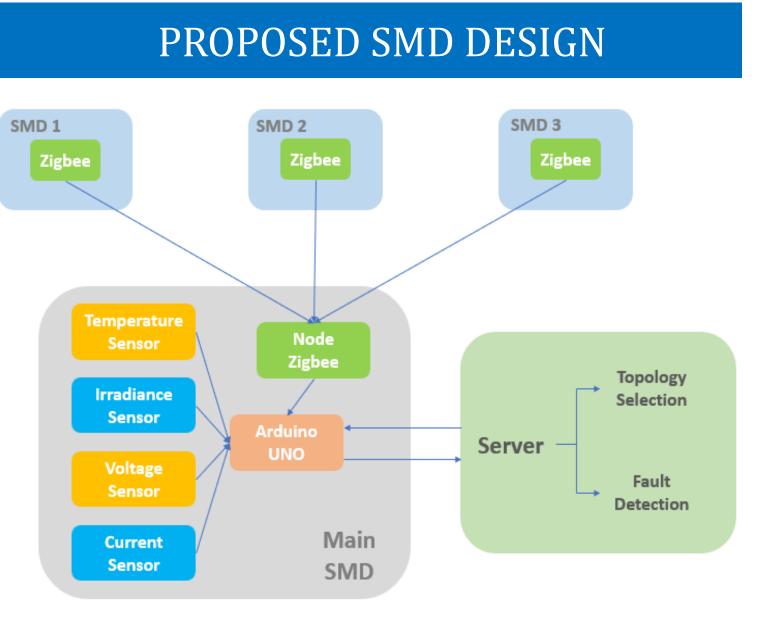
DISADVANTAGES OF AN EXISTING SMD



• Can not measure the value of Temperature

- and Irradiance with the Current SMD
- Multiple software are being used
- Slow Transmission Rate
- Only performs series, parallel or series-parallel topology reconfiguration
- Safety Concerns (It can not predict faults)



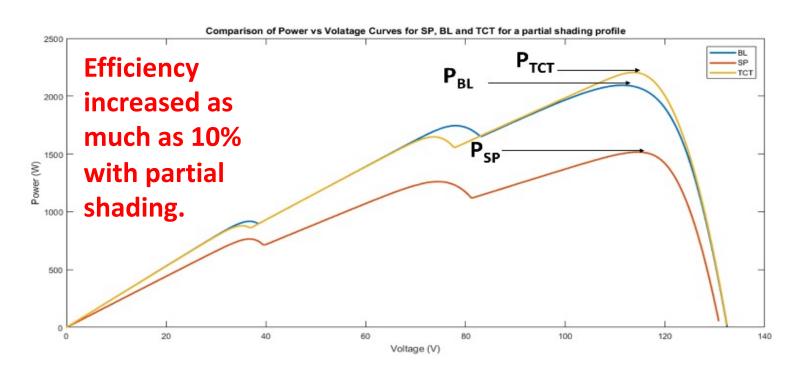


- Applications of Proposed New SMD 1. Temperature, Voltage, Current and Irradiance data collection 2. PV Array Control using Zigbee mesh Network

- - 3. Fault Detection using Neural Nets 4. Topology Optimization

TOPOLOGY OPTIMIZATION

• Need for Topology reconfiguration: Depending upon partial shading, array topologies such as series parallel (SP), Bridge Link (BL) or HoneyComb (HC) and total cross tied (TCT) produce different maximum power points



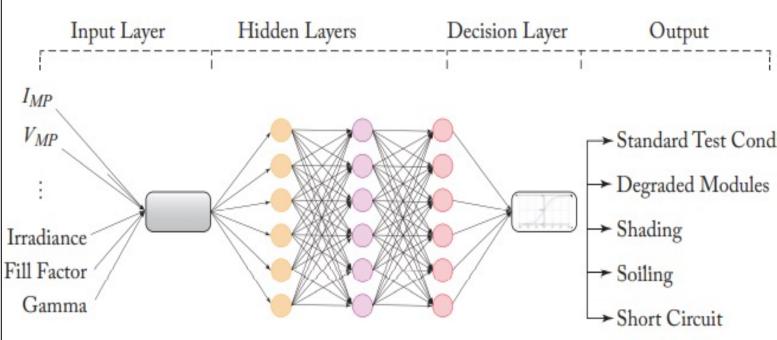
Design and Implementation of Smart Monitoring Device

TOPOLOGY SELECTION USING NEURAL NETS opologies (SP, BL or TCT) ₫< ₫< ₫< ₫< 04040404 Reading Features From the PV panels SMD with Switching Bridge Link To Serve eceived Irradiance Feature esting Data Output Trained Neural Topologies ` Ħ⁄ Ħ⁄ Ħ⁄ Considered 1. Series-Parallel 2. Total Cross Tied 3. Honeycomb 4. Bridge Link

FAULT DETECTION USING NEURAL NETS **Fault Detection**: 4 configurations (12S, 12P, 4S-3P, 3S-4P) to analyze 8 different

 \bigcirc faults.

- Topology **Optimization**: \bigcirc with partial shading. SP, TCT, BL, HC structures;
- **PV data** is used for training and testing. Ο



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- Fully Connected and Dropout Neural Nets with different probabilities used.
- Concrete Dropout reduces overfitting.
- Monte Carlo simulation and K-fold cross validation performed.

FAULT DETECTION RESULTS

Architecture	Train	Test	Test Ac-	RPN
	Accu-	Accu-	curacy	weighted
	racy(%)	racy(%)	Change	Accuracy
Fully Connected	91.62	89.34	Baseline	85.20
Concrete Dropout	91.45	89.87	+0.5%	85.25
Dropout p=0.1	89.71	89.34	0%	84.53
Dropout p=0.2	89.29	89.13	-0.21%	84.53
Dropout p=0.3	88.92	88.77	-0.57%	84.56
Dropout p=0.4	87.38	88.77	-2.14%	82.39
Dropout p=0.5	85.51	85.42	-3.92%	79.55
RFC	100	86.32	-3.02%	87.57
KNN	87.15	85.76	-3.58%	73.82
SVM	83.51	83.29	-6.05%	79.30

Comparison of various classifiers used for fault classification in PV Arrays. We note that the concrete dropout architecture performs best in terms of accuracy due to an optimized hyperparameter search within the architecture.

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[5] **Provisional Patents:** Topology: US 62/808,677 / Fault Detection: US 62/843,821

ACKNOWLEDGEMENTS

This work is supported in part by the NSF CPS Award 1646542, Poundra, and NSF I/UCRC.



performance

Output

- → Standard Test Conditions
- → Degraded Modules
- -> Shading
- → Soiling
- → Short Circuit